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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/742,224	12/22/2000	Walx Fang	4425-102	7196

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EXAMINER

BARAN, MARY C

ART UNIT	PAPER NUMBER
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2857

DATE MAILED: 02/13/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

## **DETAILED ACTION**

### ***Response to Amendment***

1. The action is responsive to the Amendment filed on 14 November 2003. Claims 1-6, 8, 10, 11, 19 and 20 are pending. Claims are amended. Claims 7, 9 and 12-18 have been cancelled.

2. The amendments filed 14 November 2003 are sufficient to overcome the prior drawing objections and 35 U.S.C. 112 first paragraph rejections.

3. The reply filed on 14 November 2003 is not fully responsive to the prior Office Action because of the following omission(s) or matter(s):

A substitute specification in proper idiomatic English was required. A substitute specification was filed; however, grammatical and spelling remain. A few examples of these errors are:

(a) On page 1 line 23, "important challenge of quality department" should be – important challenges for the quality department –.

(b) On page 2 line 14, "failing integrated circuits that induced by imperfect fabrication" should be – integrated circuit failures induced by imperfect fabrication –.

(c) On page 3 lines 1-4, "Then, in accordance with the difference between the difference between the testing environment and a normal operating environment to estimate the relation between failure rate and real time in which is the experienced time under the normal environment." should be –

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The difference between the testing environment and a normal operating environment is used to estimate the relation between failure rate and real time, which is the experienced time under the normal environment. –.

(d) On page 3 lines 14-16, boxes are shown in place of characters.

(e) On page 4 lines 21-22, “failure rate testing time relation” should be – failure rate versus testing time relation –.

(f) On page 7 line 6, “As life-time testing block 22 shows, performs” should be – Life-time testing block 22 performs –.

Applicant should note that this list is not intended to be an exhaustive list of all errors.

See 37 CFR 1.111. Since the above-mentioned reply appears to be *bona fide*, applicant is given **ONE (1) MONTH or THIRTY (30) DAYS** from the mailing date of this notice, whichever is longer, within which to supply the omission or correction in order to avoid abandonment. **EXTENSIONS OF THIS TIME PERIOD MAY BE GRANTED UNDER 37 CFR 1.136(a).**

### ***Conclusion***


4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Mary Kate B Baran whose telephone number is (571) 272-2211. The examiner can normally be reached on Monday - Friday from 8:00 am to 5:00 pm.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Marc S Hoff can be reached on (571) 272-2216. The fax phone number for the organization where this application or proceeding is assigned is 571-273-1869.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

MKB



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